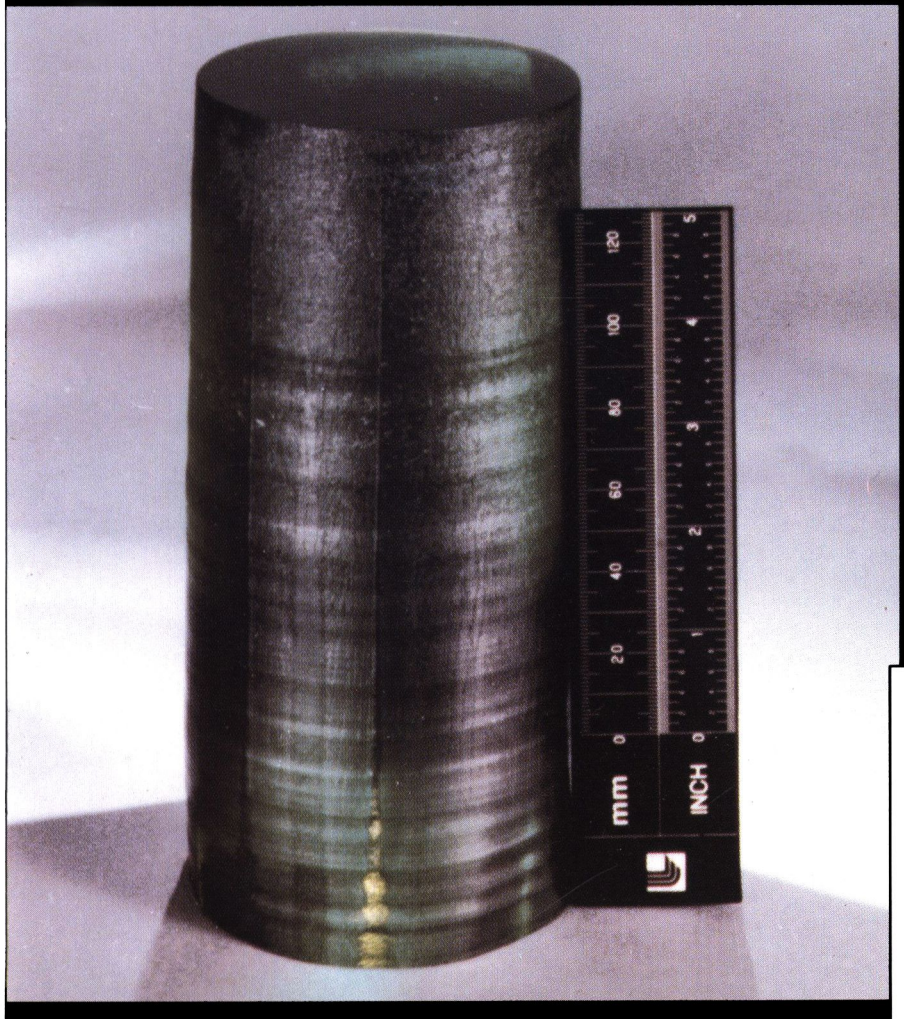
MRS BULLETIN

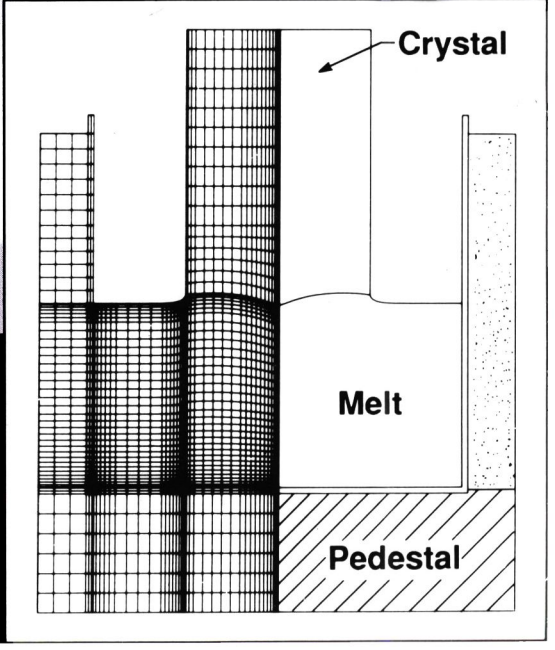
Serving the International Materials Research Community

October 1988

Volume XIII, Number 10

Crystal Growth





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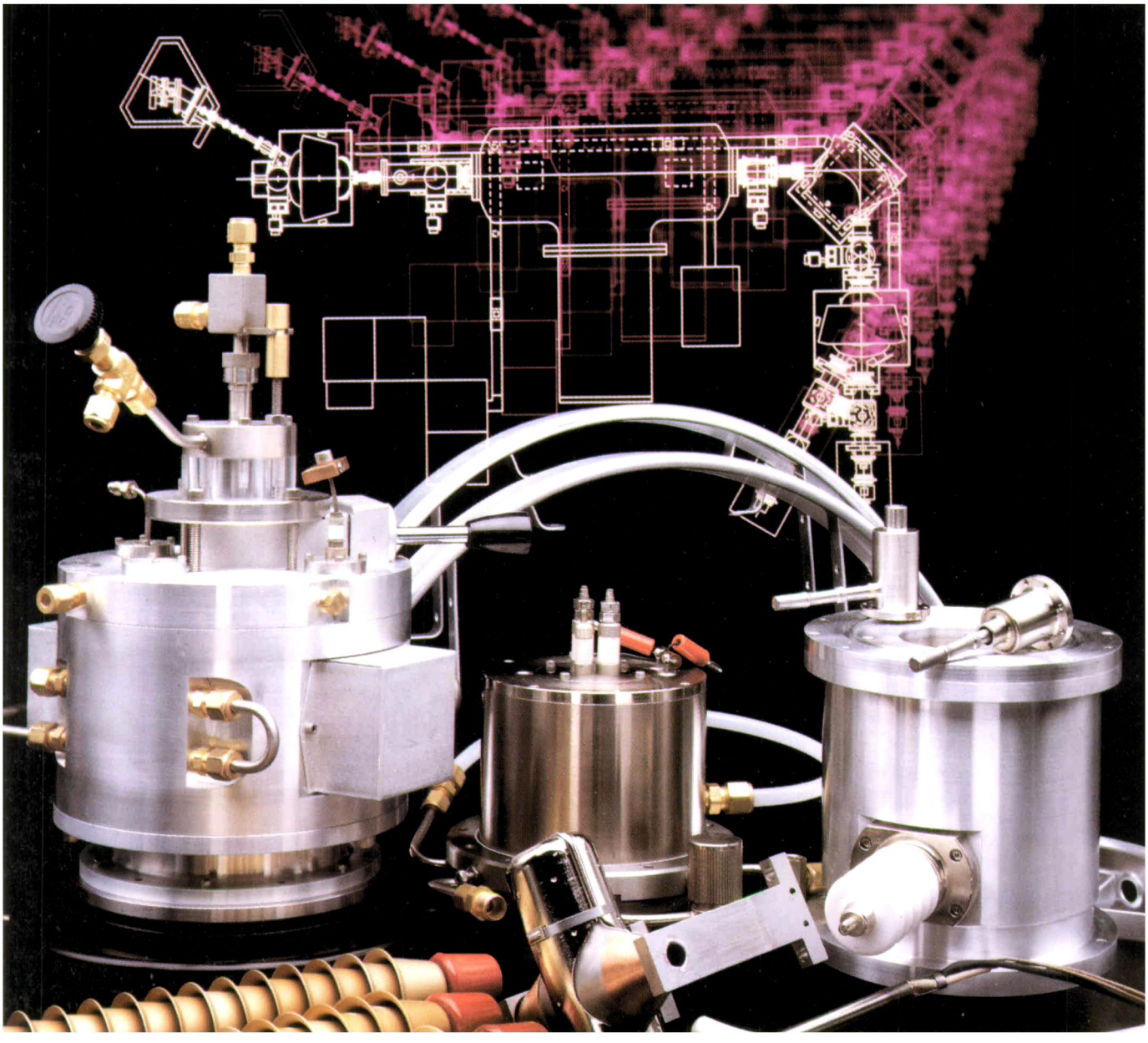

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CRYSTAL GROWTH

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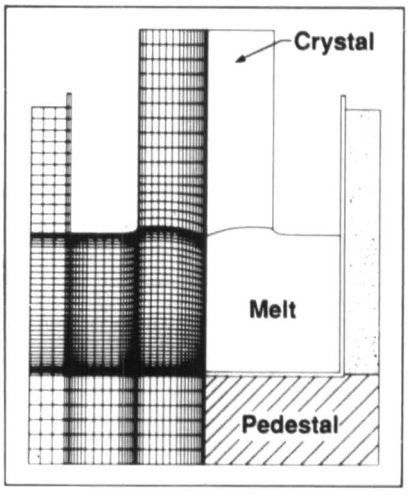

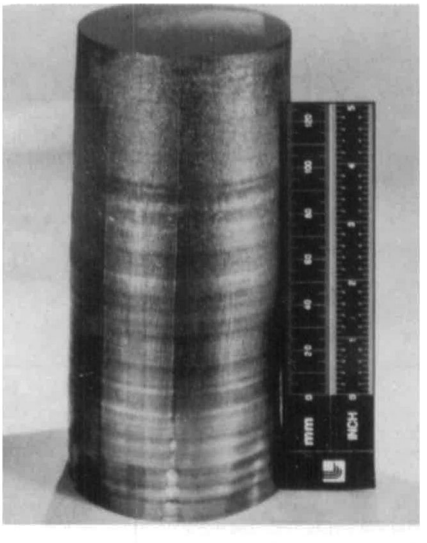

ON THE COVER: The schematic part of the illustration depicts the mathematical model for the Czochralski growth of oxide crystals. A finite element mesh is shown. The photograph shows a Nd,Cr:GSGG (neodymium- and chromium-doped gadolinium scandium gallium garnet) crystal, 9.5 cm diameter by 19.5 cm long, grown by the Czochralski method by Allied Signal, Inc., under contract to Lawrence Livermore National Laboratory. For more information see "Theoretical Modeling of Czochralski Crystal Growth" by J. J. Derby in this issue.

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The Materials Research Society (MRS) is a nonprofit scientific association founded in 1973 to promote interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 7,600 scientists from industrial, government, and university research laboratories in the United States and more than 25 countries.

The Society's interdisciplinary approach to the exchange of technical information is qualitatively different from that provided by single-discipline professional societies because it promotes technical exchange across the various fields of science affecting materials development. MRS sponsors two major international annual meetings encompassing approximately 30 topical symposia, as well as numerous single-topic scientific meetings each year. It recognizes professional and technical excellence, conducts short courses, and fosters technical exchange in various local geographic regions through Section activities and Student Chapters on university campuses.

MRS is an Affiliated Society of the American Institute of Physics and participates in the international arena of materials research through associations with professional organizations such as European MRS.

MRS publishes symposia proceedings, the *MRS BULLETIN, Journal of Materials Research,* and other current scientific developments.

For further information on the Society's activities, contact MRS Headquarters, 9800 McKnight Road, Suite 327, Pittsburgh, Pennsylvania 15237; telephone (412) 367-3003; facsimile (412) 367-4373.

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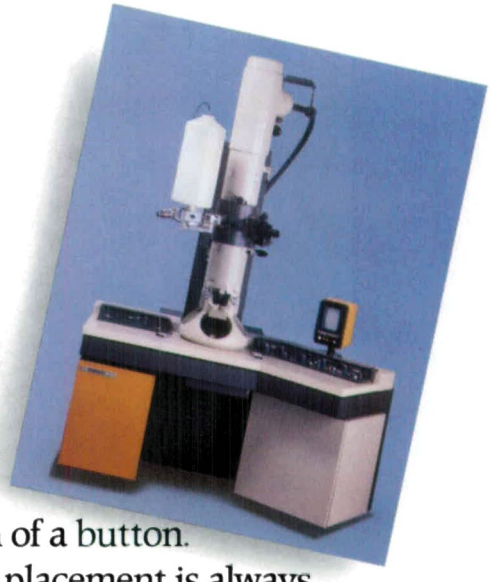

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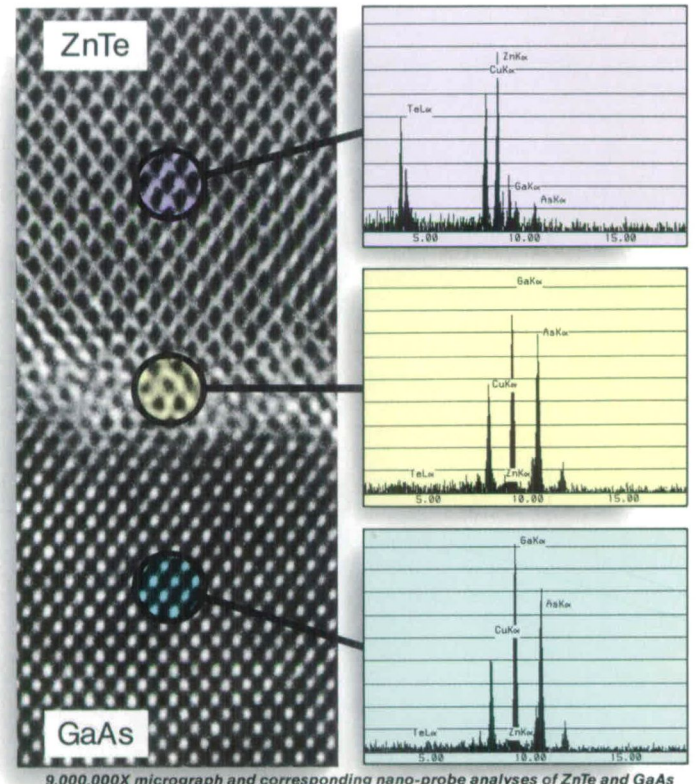

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